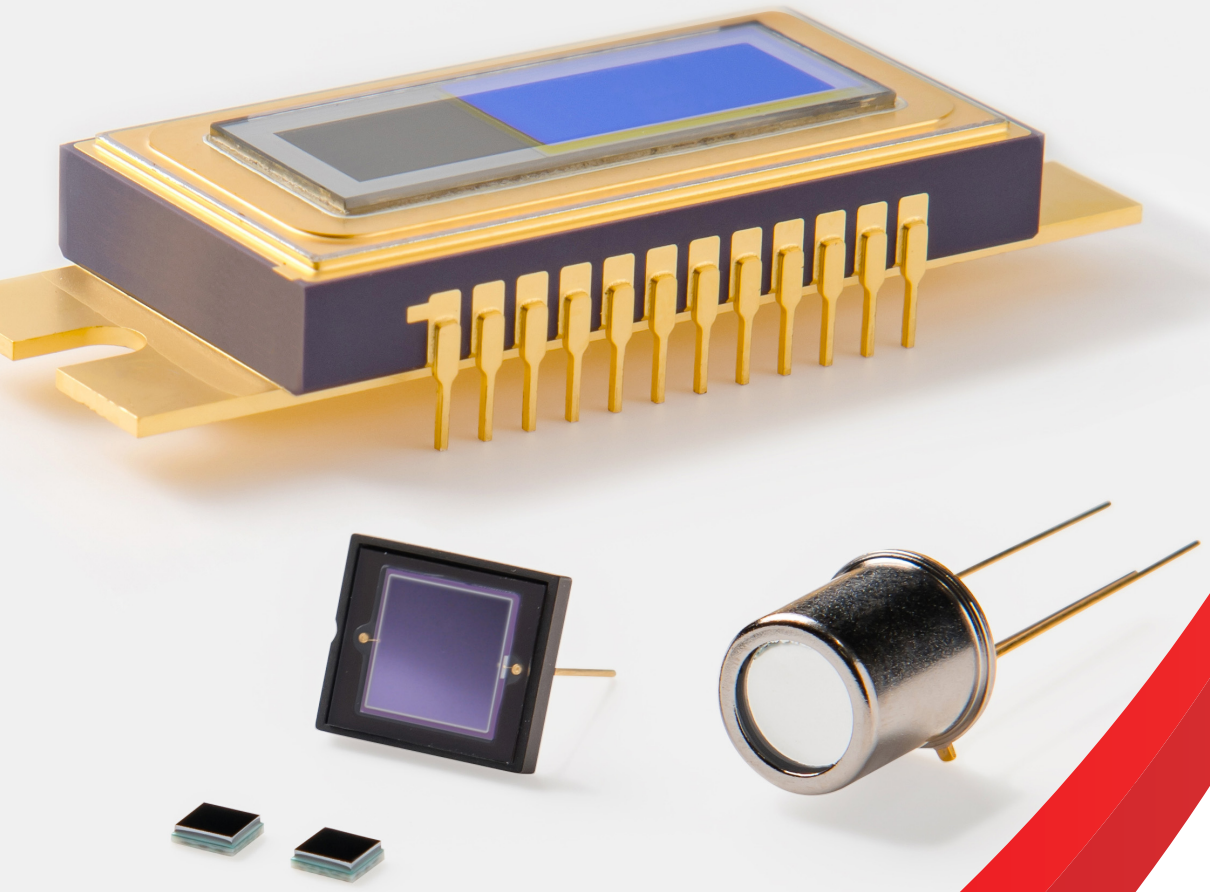
HAMAMATSU

PHOTON IS OUR BUSINESS



Devices for UV Detection

CONTENTS

P.2 What is UV ?

Features of Hamamatsu's devices for UV detection

P.4 Lineup

P.5 Product information

- Si photodiodes P.6 - 11
- Si APD P.12 - 13
- CCD area image sensors P.14
- CMOS linear image sensors P.15 - 17
- Mini-spectrometers P.18

Feb. 2025

What is ultraviolet light?

Visible light, meaning light visible to the human eye, has a spectral range of approximately 400 to 700 nm. Light with shorter wavelengths is called ultraviolet light (UV). Ultraviolet light is used in a wide range of applications as light sources and detection sensors, from industrial fields such as semiconductor manufacturing/inspection and food processing, to familiar places such as fire alarms and skin care against UV. Also, ultraviolet light has attracted attention as a key technology for sterilization and inactivation of the novel coronavirus. It is expected that UV technologies will become increasingly popular in the future.
Hamamatsu provides a wide range of detectors with features such as high UV sensitivity and high UV resistance by opto-semiconductor technologies accumulated over many years.

Features of our devices for UV detection

Feature 1 High sensitivity in UV region

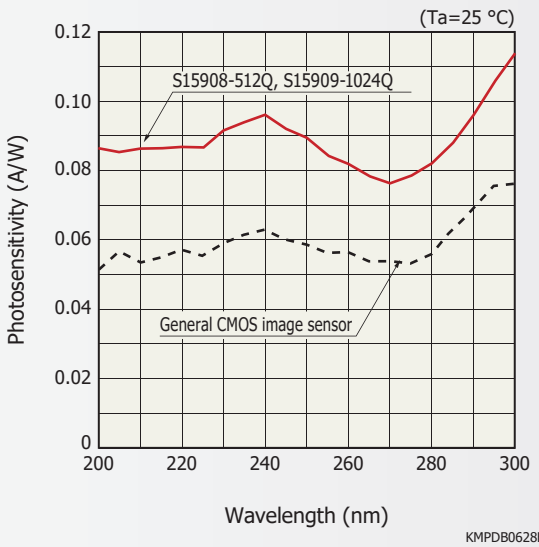
Normal silicon sensors can detect ultraviolet light, but some ultraviolet light is absorbed as it passes through window materials and packages. Hamamatsu has improved conversion efficiency by adopting a chip structure suitable for ultraviolet light detection. By adopting a window material that easily transmits ultraviolet light and a package without window, we have realized a high sensitivity in the ultraviolet region.

Feature 2 High UV resistance

Generally, resin that generates outgas, deteriorating sensitivity of the chip, is sealing to window materials and chips, in a silicon sensor. Hamamatsu uses a resin-free package to reduce generation of outgas and realize high resistance to ultraviolet light exposure.

■ Spectral response in UV region (typical example)

[CMOS linear image sensors S15908-512Q, S15909-1024Q]



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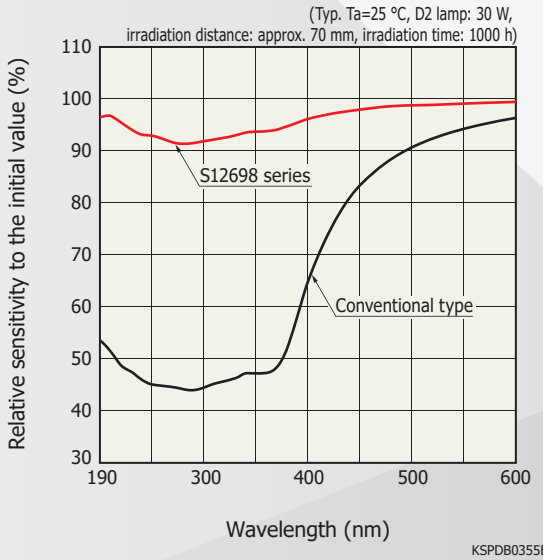
■ Variation in sensitivity due to UV exposure

[Si photodiode S12698 series]



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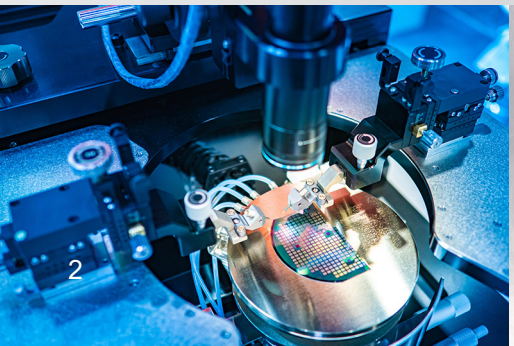
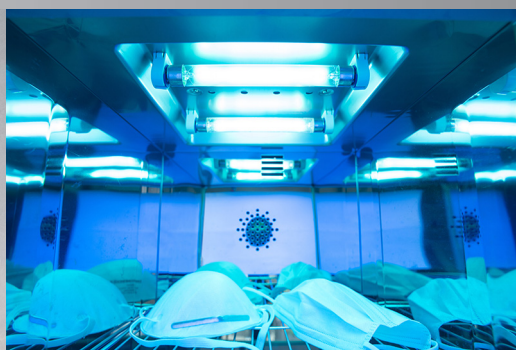
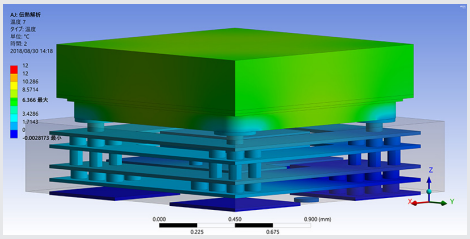


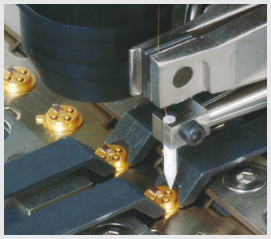


Feature 3

"Flexibility" that can be achieved by consistent in-house production

Hamamatsu has established an integrated production system in our own factory, from the design to the assembly and inspection of opto-semiconductors. That is why we are able to flexibly offer customized products to meet requirements.



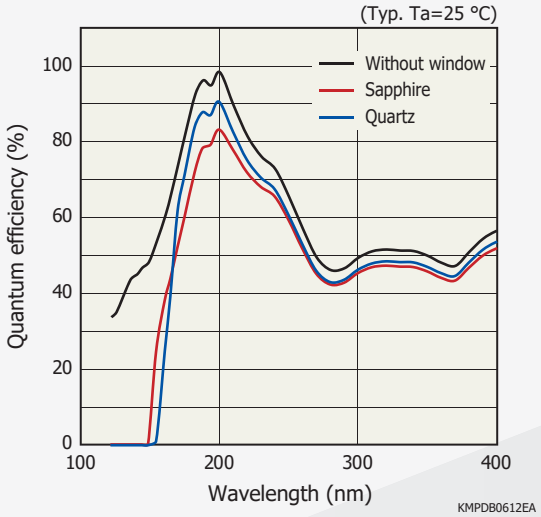


Customization examples

Window material

Choose from quartz, sapphire, no windows, and more. We can also form filters on the window material.

Spectral response of image sensor for each window material



Product example with filter

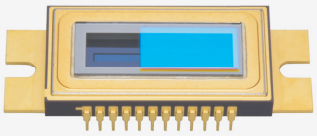
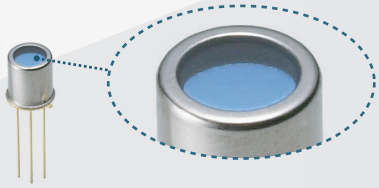


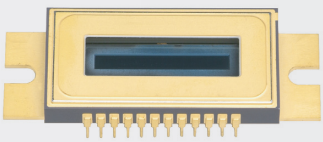
Image sensor with filter on window material



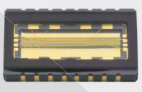
Photodiode with band-pass filter

Package

Choose from DIP (dual inline package) type, surface mount type, etc. We can also change the package shape and incorporate TE-coolers inside the package.



DIP type (built-in TE-cooler)

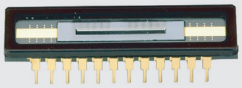


Surface mount type

Photosensitive area

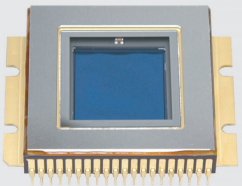
In image sensors, we can customize the pixel size and number of pixels. We offer pixel sizes from 7 × 7 µm. We can also change pixel size and number of pixels to configure other than square.

Pixel size: 14 × 14 µm
Number of pixels: 1024 × 16



CCD image sensor S10420-1004-01

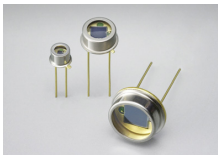
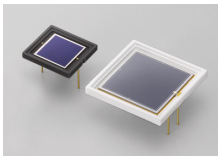
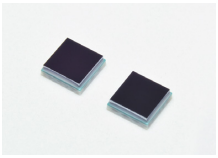
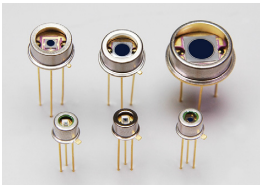
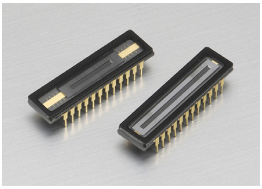
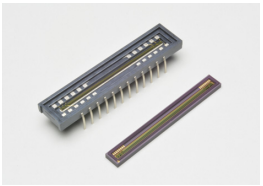
Pixel size: 12 × 12 µm
Number of pixels: 2048 × 2048



CCD area image sensor S12101

Lineup

Hamamatsu offers a wide range of detectors, including Si photodiodes, Si APDs and CCD/CMOS image sensors, as well as modules equipped with these detectors.

Product name	Type no.	Photo	Page
Si photodiodes Si PIN photodiodes	S16586 S12698 series S15289-33 S10043 S8552, S8553 S12742 series S16014-220 S1226/S1227 series S1336/S1337 series	  	P. 6 to 11
Si APDs	S14124-20 S12053 series		P. 12, 13
CCD image sensors	S10420-1106NU-01 S10420-1106NW-01		P. 14
CMOS image sensors	S11639-01 series S11639N-02 S15908-512Q, S15909-1024Q		P. 15 to 17
Mini-spectrometer	C16767MA		P. 18

Product information

Si PIN photodiode

High UV Resistance

S16586

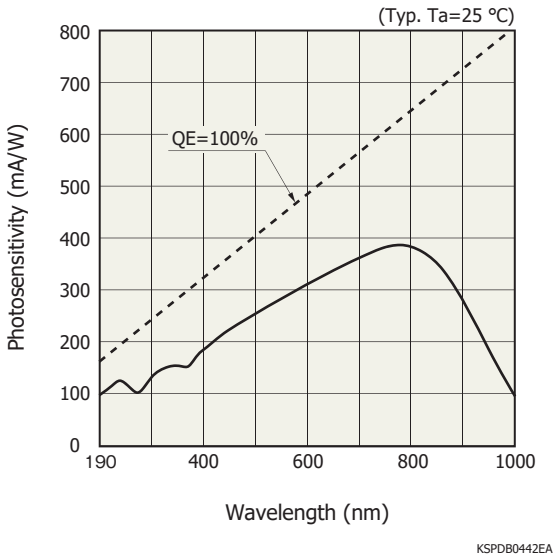
FEATURES

- With UV glass window (hermetically sealed)
- High reliability for monitoring UV light irradiation
- No resin that causes outgassing
- High-speed response

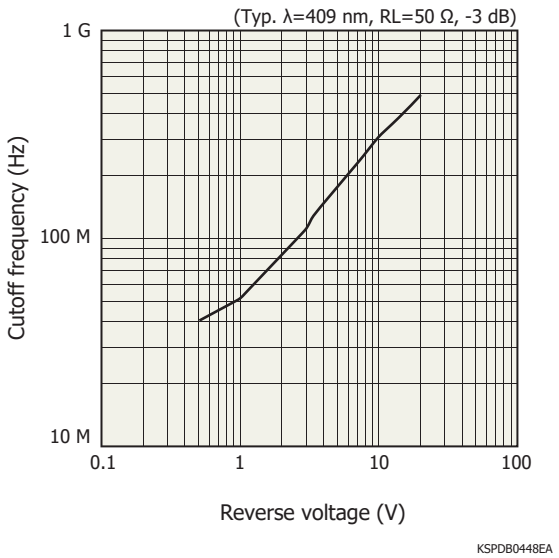
APPLICATIONS

- Power monitor for UV light sources
- Analytical instruments
- Optical measurement equipment

Spectral response



Cutoff frequency vs. Reverse voltage



Structure

Parameter	Specification	Unit
Photosensitive area size	ϕ0.8	mm
Package	TO-18	-
Window material	UV glass	-

Electrical and optical characteristics (Typ. Ta=25 °C)

Parameter	Specification	Unit
Spectral response range	190 to 1000	mm
Cutoff frequency*1	300	MHz
Terminal capacitance*2	3.5	pF

*1: V_R=10 V, R_L=50 Ω, -3 dB

*2: V_R=10 V, f=1 MHz

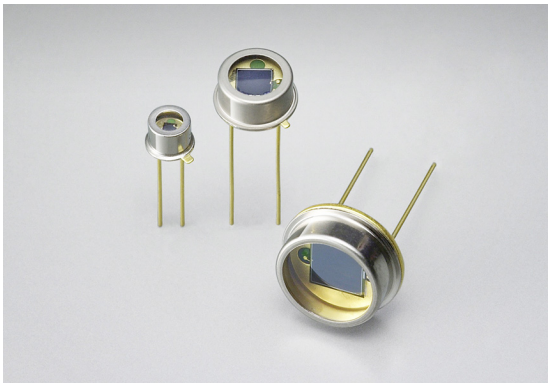
Si photodiodes

S12698 series

High UV Resistance

FEATURES

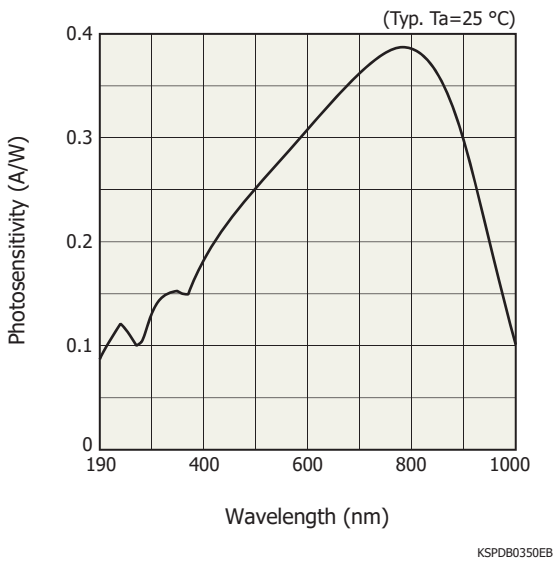
- With UV glass window (hermetically sealed)
- High reliability for monitoring UV light irradiation
- No resin that causes outgassing



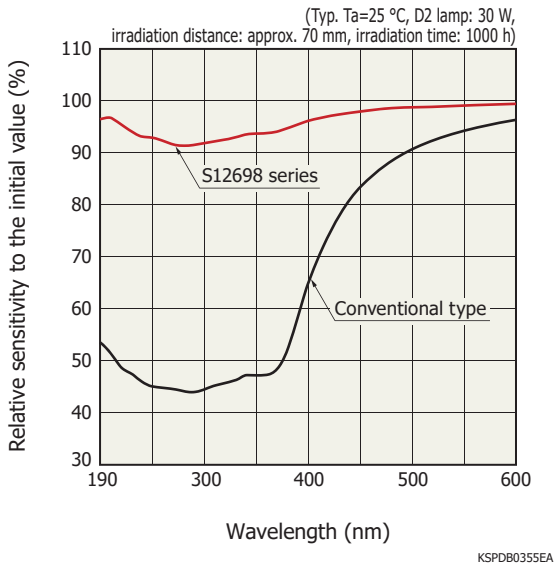
APPLICATIONS

- Power monitor for UV light sources
- Analytical instruments

Spectral response



Variation in sensitivity due to UV exposure



Structure

Parameter	S12698	S12698-01	S12698-04	S12698-02	Unit
Photosensitive area size	1.1 × 1.1	2.4 × 2.4	3.6 × 3.6	5.8 × 5.8	mm
Package	TO-18	TO-5		TO-8	-
Window material	UV glass				-

Electrical and optical characteristics (Typ. Ta=25 °C, unless otherwise noted)

Parameter	S12698	S12698-01	S12698-04	S12698-02	Unit
Spectral response range	190 to 1000				nm
Peak sensitivity wavelength	800				nm
Photosensitivity*1	0.38				A/W
Dark current (max.)*2	10	30	50	100	pA
Temp. coefficient of dark current	1.12				times/°C
Rise time*3	0.1	0.5	0.6	1.5	μs
Terminal capacitance*4	25	230	240	700	pF

*1: λ=λp *2: V_R=10 mV *3: V_R=0 V, R_L=1 kΩ, λ=655 nm *4: V_R=0 V, f=10 kHz

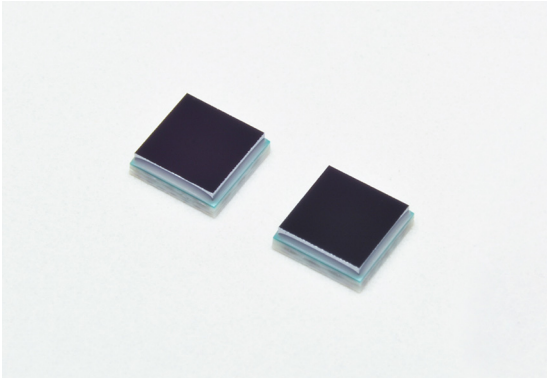
Si photodiode

High UV Resistance

S15289-33

FEATURES

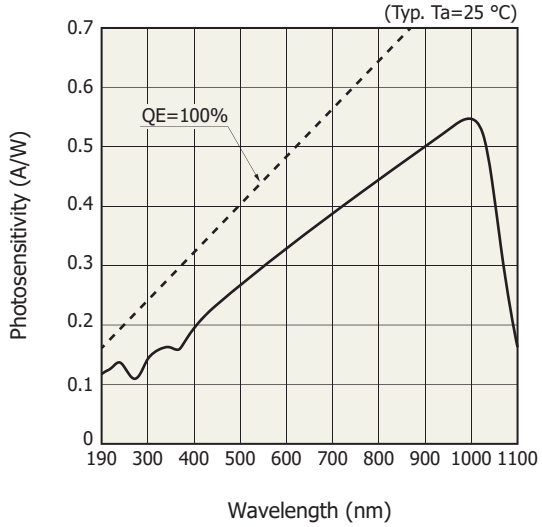
- High sensitivity in UV region: QE=75% (λ=200 nm)
- High reliability in UV light irradiation
- Compatible with lead-free solder reflow



APPLICATIONS

- Light level monitor for UV light source
- Analytical instruments

Spectral response



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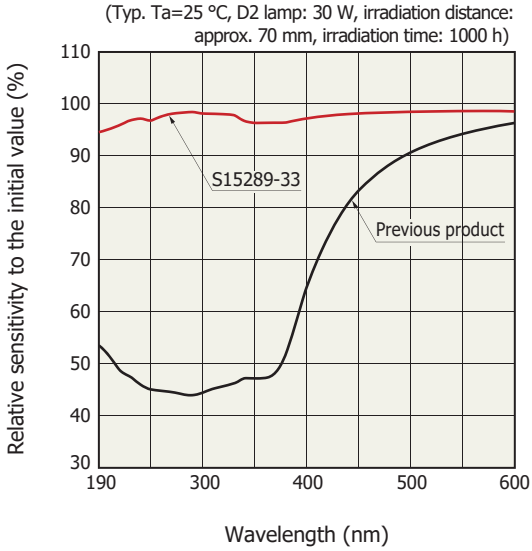
Variation in sensitivity due to UV exposure



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Structure

Parameter	Specification	Unit
Package size	3 × 3	mm
Photosensitive area size	2.5 × 2.5	mm
Package	Glass epoxy	-
Window material	None	-

Electrical and optical characteristics (Typ. Ta=25 °C)

Parameter		Specification	Unit
Spectral response range		190 to 1100	nm
Peak sensitivity wavelength		1000	nm
Photosensitivity	λ=200 nm	0.12	A/W
	λ=1000 nm	0.54	
Dark current*1		10	pA
Temp. coefficient of dark current*1		1.15	times/°C
Rise time*2		30	μs
Terminal capacitance*3		70	pF

*1: V_R=10 mV *2: V_R=0 V, R_L=1 kΩ, λ=409 nm, 10 to 90% *3: V_R=0 V, f=10 kHz

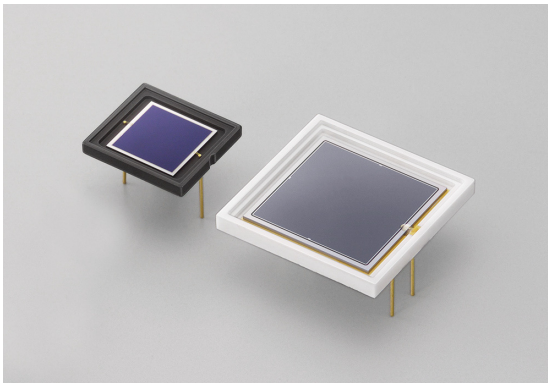
Si photodiode

for VUV Detection

S10043, S8552, S8553

FEATURES

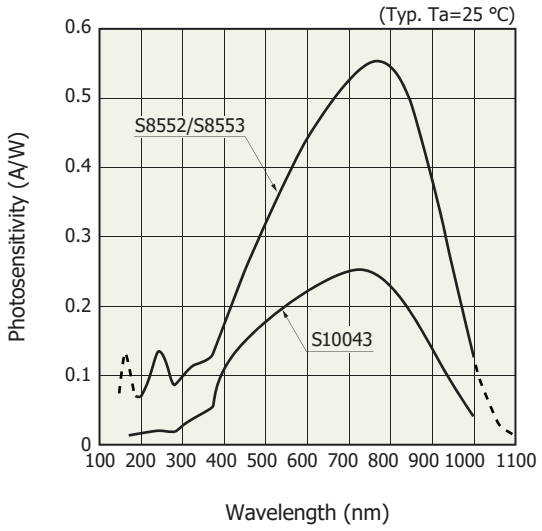
- High reliability even after exposure to ArF (λ=193 nm) excimer laser
- Windowless package



APPLICATIONS

- Vacuum UV monitor
- Excimer laser monitor

Spectral response



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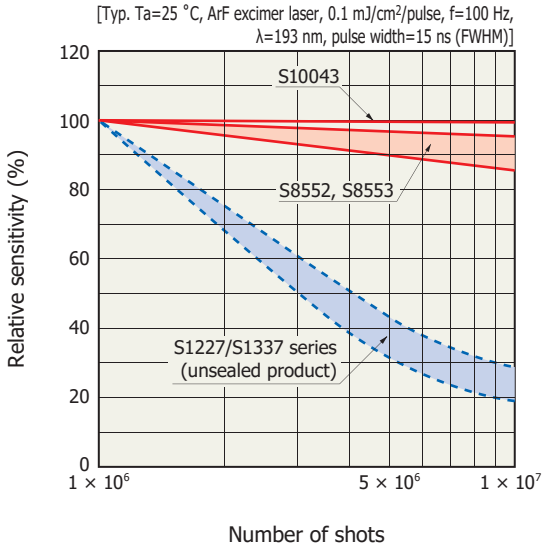
Variation in sensitivity due to VUV exposure



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Structure

Parameter	S10043	S8552	S8553	Unit
Photosensitive area size	10 × 10		18 × 18	mm
Package	Ceramic			-
Window material	None			-

Electrical and optical characteristics (Typ. Ta=25 °C)

Parameter	S10043	S8552	S8553	Unit
Spectral response range	190 to 1000			nm
Peak sensitivity wavelength	720	780		nm
Photosensitivity*1	15	60		mA/W
Dark current*2	0.1	0.05	0.1	nA
Rise time*3	9		18	μs
Terminal capacitance*4	4		8	nF

*1: λ=193 nm *2: V_R=10 mV *3: V_R=0 V, R_L=1 kΩ, 10 to 90% *4: V_R=0 V, f=10 kHz

Si photodiodes

for Monochromatic Light

S12742 series, S16014-220

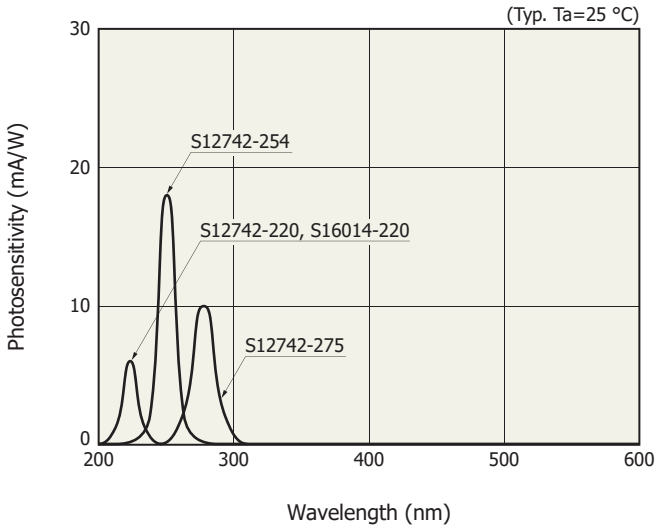
FEATURES

- With monochromatic light filter
- Narrow spectral response half width (FWHM)

APPLICATIONS

- Water quality and atmosphere analysis
- UV monitors (mercury lamp, etc.)

Spectral response



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The S12742 series can be customized to support other peak sensitivity wavelengths such as 340 nm and 560 nm (made-to-order products).

Structure

Parameter	S16014-220	S12742 series	Unit
Photosensitive area size	1.1 × 1.1	3.61 × 3.61	mm
Package	TO-18	TO-5	-
Window material	With filter		-

Electrical and optical characteristics (Typ. Ta=25 °C, unless otherwise noted)

	S16014-220	S12742-220	S12742-254	S12742-275	Unit
Center wavelength	220		254	275	mm
Spectral response half width	11		10		nm
Photosensitivity*1	6		18	10	mA/W
Dark current (max.)*2	10	25			pA
Rise time*3	0.1	1			μs
Terminal capacitance*4	25	500			pF

*1: λ=Center wavelength *2: V_R=10 mV *3: V_R=0 V, R_L=1 kΩ *4: V_R=0 V, f=10 kHz

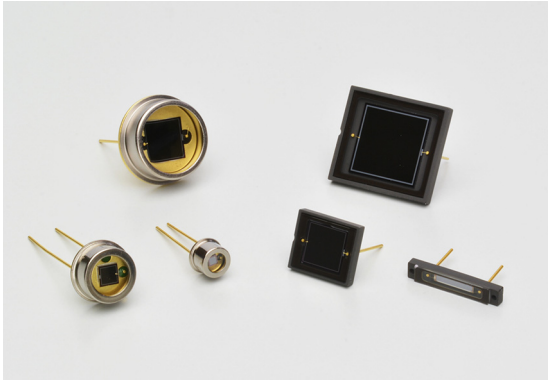
Si photodiodes

High UV Sensitivity

S1226 / S1227 / S1336 / S1337 series

FEATURES

- High UV sensitivity
- Near IR sensitivity suppressed type (S1226/S1227 series)
- High sensitivity in UV to near IR range (S1336/S1337 series)

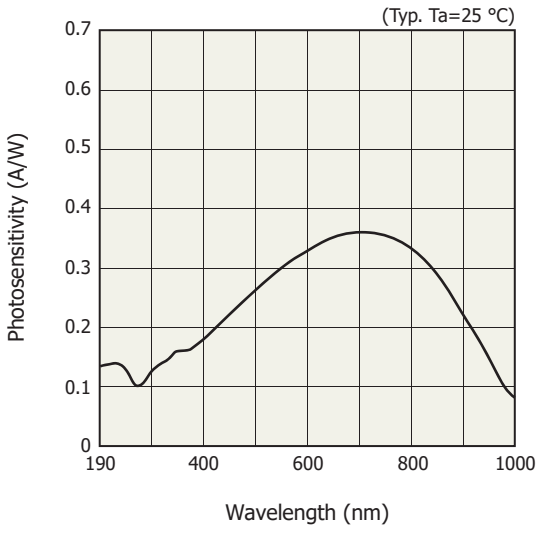


APPLICATIONS

- Analytical instruments
- Optical measurement equipment

Spectral response

S1226/S1227-BQ series



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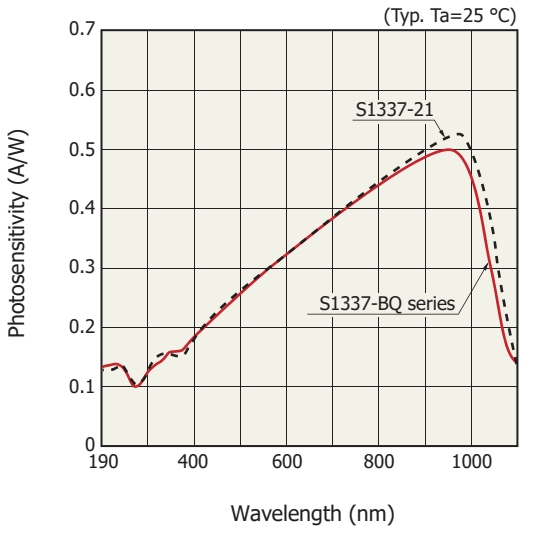
S1336/S1337-BQ series



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Structure

Parameter	S1226-BQ series	S1227-BQ series	S1336-BQ series	S1337-BQ series	Unit
Photosensitive area size	1.1 × 1.1 to 5.8 × 5.8	1.1 × 5.9 to 10 × 10	1.1 × 1.1 to 5.8 × 5.8	1.1 × 5.9 to 18 × 18	mm
Package	Metal	Ceramic	Metal	Ceramic	-
Window material	Quartz glass				-

Electrical and optical characteristics (Typ. Ta=25 °C)

Parameter	S1226/S1227-BQ series	S1336/S1337-BQ series	Unit
Spectral response range	190 to 1000	190 to 1100	nm
Peak sensitivity wavelength	720	960	nm
Photosensitivity*1	0.12		A/W

*1: λ=200 nm

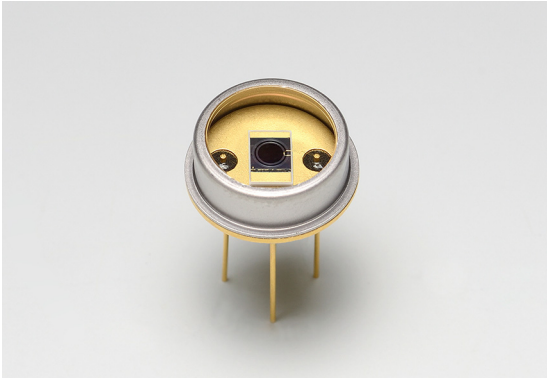
Si APD

S14124-20

High UV Sensitivity

FEATURES

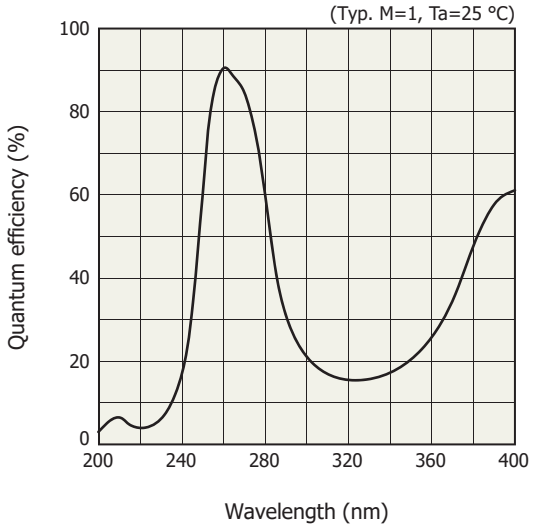
- High sensitivity: QE=87% (λ=266 nm)
- Low capacitance
- Low noise



APPLICATIONS

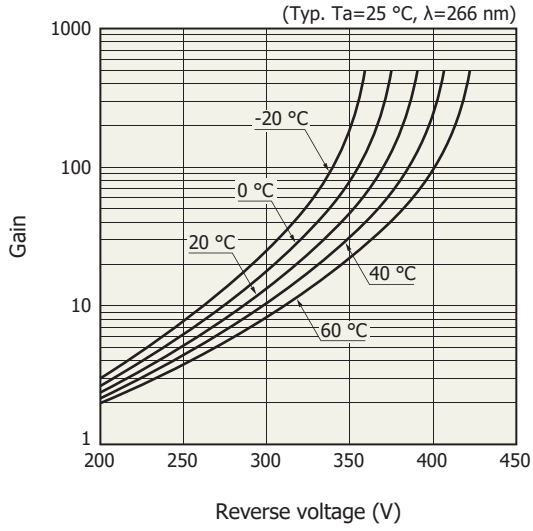
- Semiconductor inspection system
- Laser processing equipment

Spectral response



KAPDB0568EA

Gain vs. reverse voltage



KAPDB0570EA

Structure

Parameter	Specification	Unit
Photosensitive area size	ϕ2.0	mm
Package	TO-8	-
Window material	AR-coated quartz	-

Electrical and optical characteristics (Typ. Ta=25 °C, unless otherwise noted)

Parameter	Specification	Unit
Peak sensitivity wavelength*1	600	nm
Breakdown voltage*2	400	V
Temp. coefficient of breakdown voltage	0.78	V/°C
Dark current (max.)*1	10	nA
Terminal capacitance*3	11	pF
Cutoff frequency*4	250	MHz
Gain*5	50 to 400	-

*1: M=50 *2: I_D=10 μA *3: M=50, f=1 MHz *4: M=50, λ=266 nm, R_L=50 Ω, -3dB *5: λ=266 nm

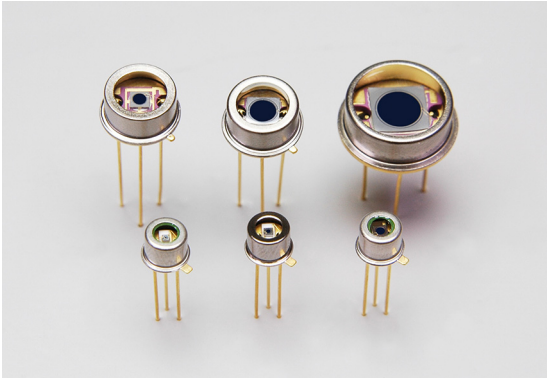
Si APD

S12053 series

High UV Sensitivity

FEATURES

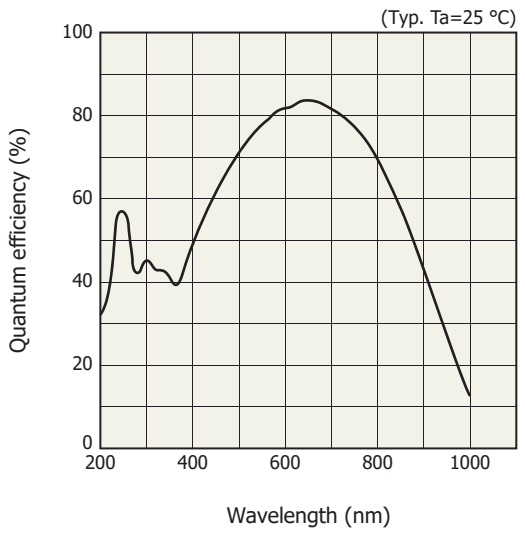
- High sensitivity in UV to visible range
- Low noise



APPLICATIONS

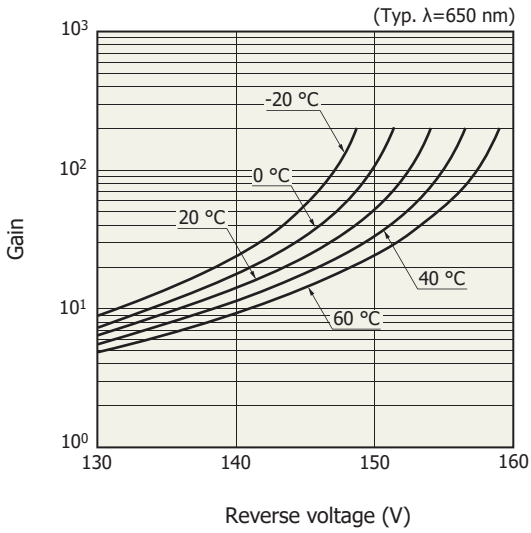
- Low-light-level measurement
- Analytical instruments

Spectral response



KAPDB0023EB

Gain vs. reverse voltage



KAPDB0011EC

Structure

Parameter	S12053-02	S12053-05	S12053-10	Unit
Photosensitive area size	ϕ0.2	ϕ0.5	ϕ1.0	mm
Package	TO-18			-
Window material	UV glass			-

Electrical and optical characteristics (Typ. Ta=25 °C)

Parameter	S12053-02	S12053-05	S12053-10	Unit
Spectral response range	200 to 1000			nm
Peak sensitivity wavelength	620			nm
Breakdown voltage*1	150			V
Temp. coefficient of breakdown voltage	0.14			V/°C
Dark current	0.2			nA
Terminal capacitance*2	2	5	15	pF
Cutoff frequency*3	900	400	250	MHz
Gain*4	50			-

*1: I_D=100 μA *2: M=50 *3: R_L=50 Ω *4: λ=650 nm

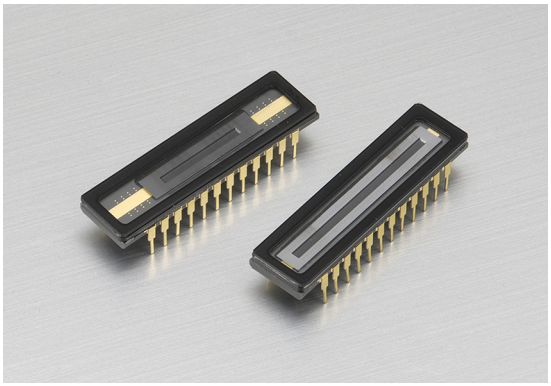
CCD area image sensors

High UV Resistance

S10420-1106NU-01, S10420-1106NW-01

FEATURES

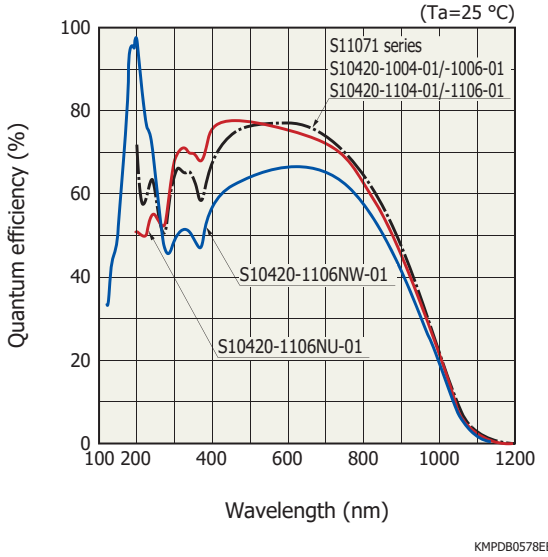
- Improved etaloning characteristics
- High UV resistance
- With anti-blooming function



APPLICATIONS

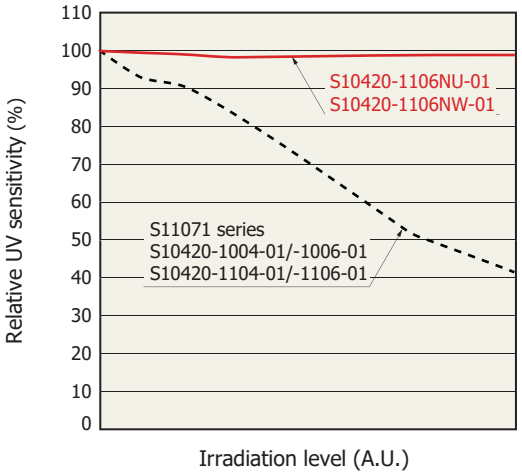
- Spectrometers

Spectral response (typical example)



KMPDB0578EB

Variation in sensitivity due to UV exposure



* The graph is plotted as 100% at the average spectral response (λ=200 to 400 nm) before irradiation.

KMPDB0610EA

Structure

Parameter	Specification	Unit
Pixel size	14 × 14	μm
Number of effective pixels	2048 × 64	-
Package	24-pin ceramic DIP	-
Window material	Quartz glass	-

Electrical and optical characteristics (Typ. Ta=25 °C, unless otherwise noted)

Parameter		S10420-1106NU-01	S10420-1106NW-01	Unit
Spectral response range		200 to 1100	120 to 1100	nm
Full well capacity	Vertical	60		ke⁻
	Horizontal	300		
Conversion efficiency		6.5		μV/e⁻
Dark current		50		e⁻/pixel/s
Readout noise*1		6		e⁻ rms
Dynamic range*2		50000		-
Photoresponse nonuniformity*3		±3		%

*1: Ta=-40 °C, operating frequency: 20 kHz *2: Dynamic range = Full well capacity / Readout noise

*3: Measured at one-half of the saturation output (full well capacity) using LED light (peak emission wavelength: 660 nm)

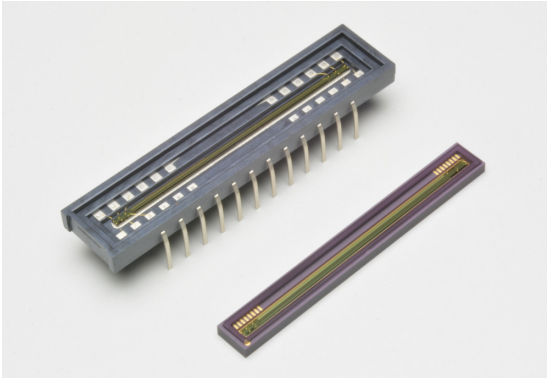
CMOS linear image sensor

High UV Sensitivity

S11639-01, S11639-21

FEATURES

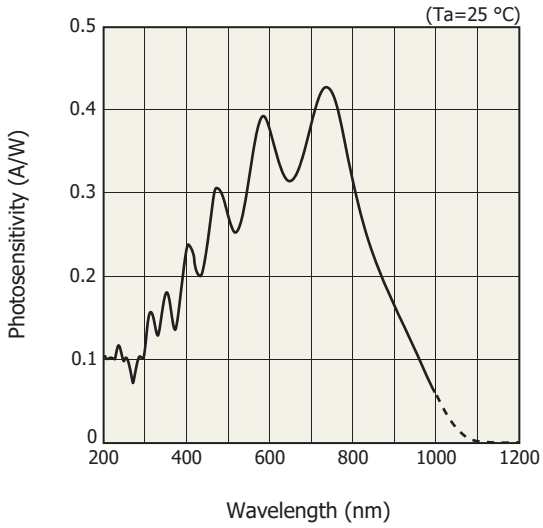
- High sensitivity in UV to near IR region
- Simultaneous charge integration for all pixels
- 5 V single power supply operation
- Built-in timing generator allows operation with only start and clock pulse inputs



APPLICATIONS

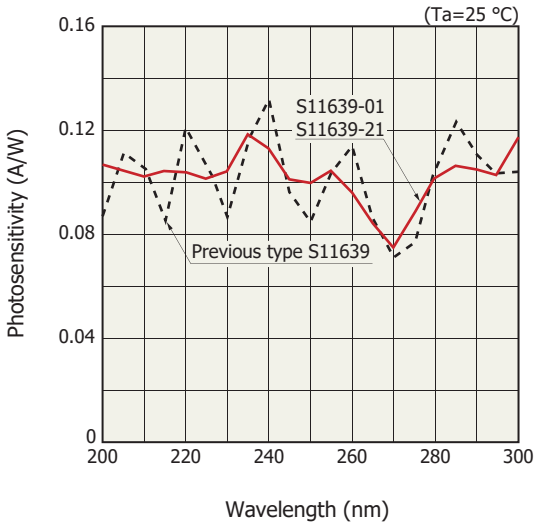
- Spectrometers
- Position detection

Spectral response (typical example)



KMPDB0467EB

Spectral response in UV region (typical example)



KMPDB0718EA

Structure

Parameter	S11639-01	S11639-21	Unit
Pixel height	200		µm
Pixel pitch	14		µm
Number of effective pixels	2048		-
Package	LCP (liquid crystal polymer)	Surface mount type ceramic	-
Window material	Quartz glass		-

Electrical and optical characteristics (Typ. Ta=25 °C)

Parameter	Specification	Unit
Spectral response range	200 to 1000	nm
Saturation output voltage*1	2.0	V
Conversion efficiency	20	µV/e⁻
Dark output voltage*2	0.2	mV
Readout noise	0.4	mV rms
Dynamic range*3	5000	-
Photoresponse nonuniformity*4	±2	%

*1: Difference from output offset voltage *2: Integration time=10 ms *3: Dynamic range = Saturation output voltage / Readout noise
*4: Measured at one-half of the saturation output

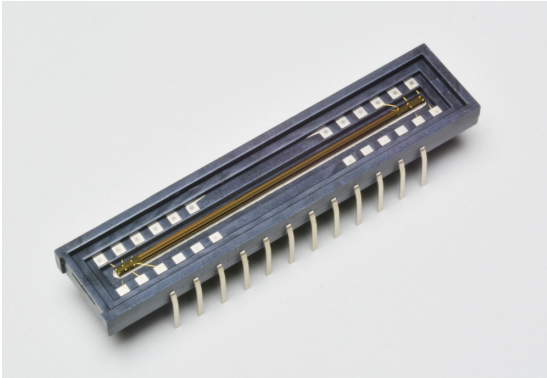
CMOS linear image sensor

High sensitivity in vacuum UV region

S11639N-02

FEATURES

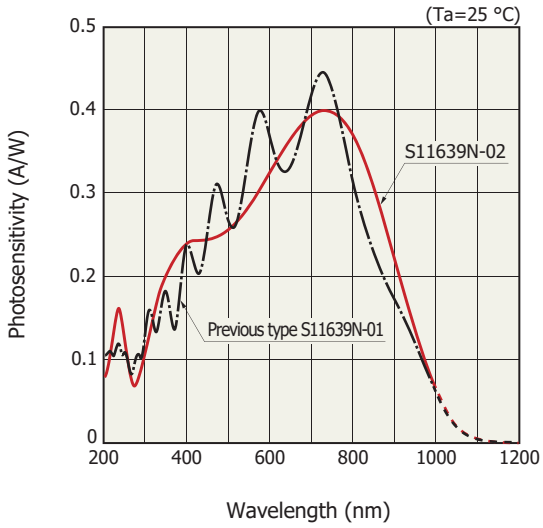
- High sensitivity in VUV to near IR region
- Simultaneous charge integration for all pixels
- 5 V single power supply operation
- Built-in timing generator allows operation with only start and clock pulse inputs



APPLICATIONS

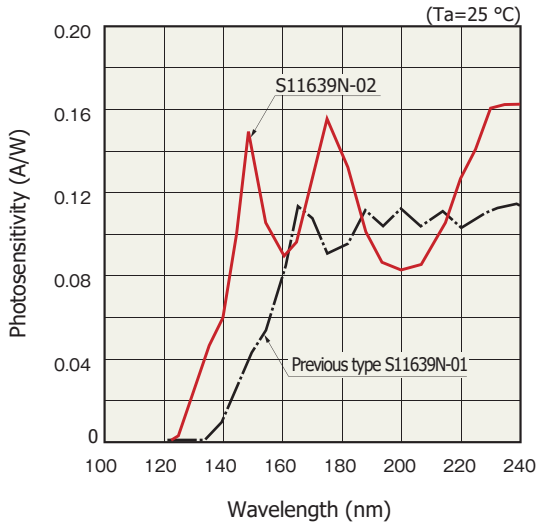
- Spectrometers

Spectral response (typical example)



KMPDB0537JB

Spectral response in UV region (typical example)



KMPDB0538JA

Structure

Parameter	Specification	Unit
Pixel height	200	µm
Pixel pitch	14	µm
Number of effective pixels	2048	-
Package	LCP (liquid crystal polymer)	-
Window material	None*1	-

*1: Temporary window
The S11639N-02 is shipped with the package held with glass tape. Remove the grass when using.

Electrical and optical characteristics (Typ. Ta=25 °C)

Parameter	Specification	Unit
Spectral response range	140 to 1000	nm
Saturation output voltage*2	2.0	V
Conversion efficiency	20	µV/e⁻
Dark output voltage*3	0.2	mV
Readout noise	0.4	mV rms
Dynamic range*4	5000	-
Photoresponse nonuniformity*5	±2	%

*2: Difference from output offset voltage *3: Integration time=10 ms *4: Dynamic range = Saturation output voltage / Readout noise
*5: Measured at one-half of the saturation output

CMOS linear image sensors

High UV Sensitivity

S15908-512Q, S15909-1024Q

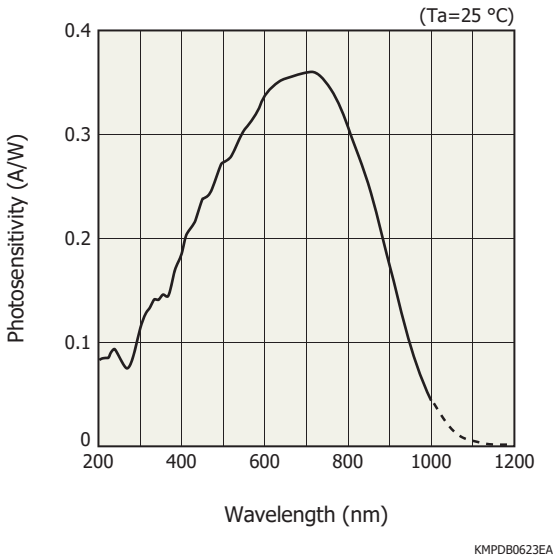
FEATURES

- Suppress fringe of spectral response curve from UV to near IR
- Low dark current
- Large saturation output charge
- Variable integration time for each pixel

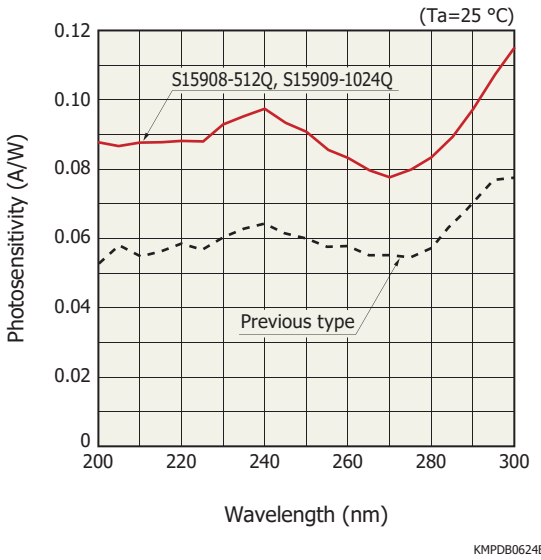
APPLICATIONS

- Spectrophotometry

Spectral response (typical example)



Spectral response in UV region (typical example)



Structure

Parameter	S15908-512Q	S15909-1024Q	Unit
Pixel height	2.5		mm
Pixel pitch	50	25	µm
Number of effective pixels	512	1024	-
Package	Ceramic		-
Window material	Quartz		-

Electrical and optical characteristics (Typ. Ta=25 °C, unless otherwise noted)

Parameter	S15908-512Q	S15909-1024Q	Unit
Spectral response range	200 to 1000		nm
Saturation output charge	200	100	pC
Dark current	0.03		pA
Photo response non-uniformity (max.)*	±3		%

* Measured at one-half of the saturation output

Mini-spectrometers

C16767MA

High UV Sensitivity

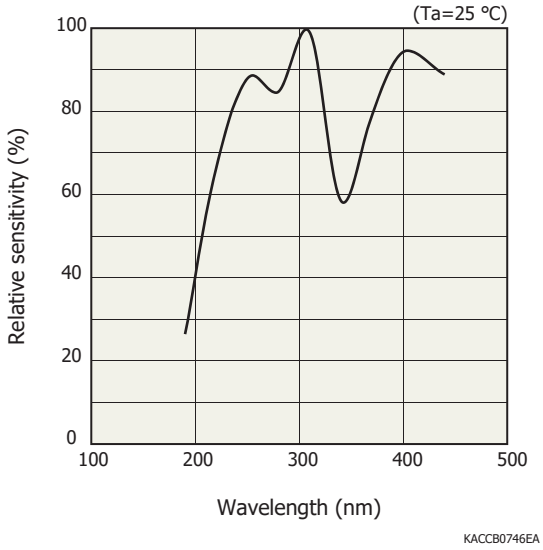
FEATURES

- Fingertip size: 20.1 × 12.5 × 10.1 mm
- Weight: 5 g
- Spectral response range: 190 to 440 nm
- Spectral resolution: 8 nm max.
- Supports synchronized integration

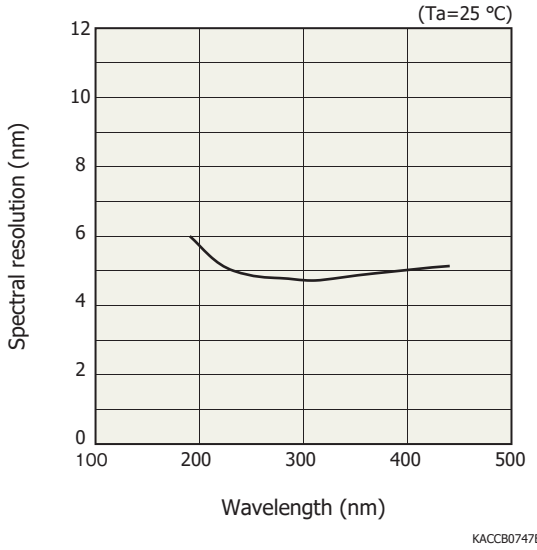
APPLICATIONS

- Food inspection
- Biometry (POC)
- Tester for UV-LEDs, etc

Spectral response in UV region (typical example)



Spectral resolution vs. wavelength (typical example)



Electrical and optical characteristics (Typ. Ta=25 °C), structure

Parameter	Symbol	Specification	Unit
Spectral response range	λ	190 to 440	nm
Spectral resolution (FWHM)	-	5.5	nm
Wavelength reproducibility	λr	-0.5 to +0.5	nm
Wavelength temperature dependence	λTd	-0.07 to +0.07	nm/℃
Dimensions (W × D × H)	-	20.1 × 12.5 × 10.1	mm
Weight	-	5	g

Evaluation circuit C13016 for mini-spectrometer micro series (sold separately)

The C13016 is a circuit board designed to simply evaluate the characteristics of the mini-spectrometer micro series. The characteristics of the micro series can be evaluated using the evaluation software by connecting the mini-spectrometer micro series to a PC with a USB cable A9160 (AB type, sold separately).

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